

Agilent Medalist i3070 07.00pc Software Package

Software Release Date: April, 2007

System Requirements: Agilent Medalist i3070 or Test Development PC

Controller Requirements: Windows PC **Operating System:** Microsoft Windows XP

Software Requirement: Agilent Medalist i3070 07.00p

This Software Patch may be installed only on MS Windows systems with i3070 07.00p software release installed. It can be installed on systems with i3070 Test System Software or i3070 Development Software.

The Software Update must be installed by the administrator login (or a login with administrator privileges).

To download and install the 07.00pc Software Update on Windows systems running the i3070 07.00p software release:

- 1. Click on "i3070 07.00pc 0307 WN" Download. Save this file to disk.
- 2. Close all open programs.
- 3. Go to the directory in which the file was saved and Double-click on Agilenti3070_07.00pc.exe.
- 4. Follow the Install Shield instructions for installation.
- 5. To validate that the software installed correctly, bring up a Korn Shell window. On the menu bar, click START then click Programs then click Agilent ICT then click Korn Shell. In the Korn Shell window, type "version" and press Enter. The software revision "Patch i3070 07.00pc 0307 WN released on April 2007"should display at the end of the output.
- 6. Delete the Agilenti3070_07.00pc.exe.

Agilent Medalist i3070 07.00pc Software Release Bulletin

This is a Software Patch for Agilent Medalist i3070 07.00p for Windows.

You must already have version i3070 07.00p on your computer before you install the 07.00pc software patch.

Software patch 07.00pc addresses these issues:

Change Request Identification	Description
CR28155	Summary report is now provided to show number of pins tested during iVTEP/NPM autodebug
CR28286	Placement problem of Mint Pin and cross-hair if only Bank 1 is used to develop the board has been fixed
CR28464	The command "ipg; scanworks" doesn't take too long to complete now
CR28489	Scanworks PCI-400 dgn test 11019 doesn't give a false failure now
CR27832	User Interface can display <npm> tested data now</npm>
CR28853	The engineer debug UI will start to refresh the UI within two seconds after running VTEP/iVTEP autodebug on large device with many pins.
CR28854	Improved performance of auto-Optimizer for analog test
CR28855	Expand license Perl script to break license files into individual file entry
CR28749	Calibration values for Mux'ed hybrid pin cards are now loaded at boot time
CR27992	The Operator and Engineer UI for UnMux system will function normally and not freeze during DUT board test
CR28884	i3070: Display Graphic for testjet/vtep is now shown
CR28899	i3070: Can "Add guard" or "Select Guard" and Run for panelize board now